

Search Notes

Application/Control No.

10/664,500

Examiner

Maikhanh Nguyen

Applicant(s)/Patent under
Reexamination

YALOVSKY, MARK

Art Unit

2176

SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|------------|----------|
| 715 | 530 | 5/5/2006 | MK |
| 715 | 517,519 | 5/5/2006 | MK |
| 715 | 520 | 5/5/2006 | MK |
| 707 | 100 | 5/5/2006 | MK |
| Updated | Search | 11/15/2006 | MK |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|------------|------|
| Inventor Name Search | 5/5/2006 | MK |
| West Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) | 5/5/2006 | MK |
| West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout | 11/15/2006 | MK |
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